

Search Notes



Application/Control No.

10/712,748

Examiner

John B. Walsh

Applicant(s)/Patent under Reexamination

CHAN ET AL.

Art Unit

2151

SEARCHED

| Class | Subclass | Date | Examiner |
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| 709 | 250 | 8/3/2006 | JW |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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| USPGPUB | test need of claims (see attached search history) | 8/3/2006 | JW |
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)

| | DATE | EXMR |
|--|----------|------|
| text search (see attached search history) | 8/3/2006 | JW |
| backward/forward citations of cited references (see attached search history) | 8/3/2006 | JW |
| inventor name search | 8/3/2006 | JW |
| IEEE xplore database search (see attached search history page) | 8/3/2006 | JW |
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